	Туре	L#	Hits	Search Text	DBs
1	BRS	L1	2417	257/774.ccls.	US-PGPUB; USPAT; USOCR; FPRS
2	BRS	L2	1217	257/750.ccls.	US-PGPUB; USPAT; USOCR; FPRS
3	BRS	L3	3390	257/758.ccls.	US-PGPUB; USPAT; USOCR; FPRS
4	BRS	L4	1948	257/738.ccls.	US-PGPUB; USPAT; USOCR; FPRS
5	BRS	L5	1393	257/780.ccls.	US-PGPUB; USPAT; USOCR; FPRS
6	BRS	L6	2817	257/778.ccls.	US-PGPUB; USPAT; USOCR; FPRS
7	BRS	L7	222	257/750.ccls.	EPO; JPO; DERWENT; IBM_TDB
8	BRS	L8	53	257/738.ccls.	EPO; JPO; DERWENT; IBM_TDB

	Туре	L#	Hits	Search Text	DBs
9	BRS	L9	0	((chip or device) and (bump or ball) and external and (terminal or electrode) and (insulating or dielectric) and stress and hardness and (conduct\$3 or wiring)) clm.	US-PGPUB